

TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (π -MOSIII)

2SK2845

Chopper Regulator, DC/DC Converter and Motor Drive Applications

- Low drain-source ON-resistance : $R_{DS(ON)} = 8.0 \Omega$ (typ.)
- High forward transfer admittance : $|Y_{fs}| = 0.9 \text{ S}$ (typ.)
- Low leakage current : $I_{DSS} = 100 \mu\text{A}$ (max) ($V_{DS} = 720 \text{ V}$)
- Enhancement mode : $V_{th} = 2.0 \sim 4.0 \text{ V}$ ($V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ mA}$)

Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristic	Symbol	Rating	Unit
Drain-source voltage	V_{DSS}	900	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	V_{DGR}	900	V
Gate-source voltage	V_{GSS}	± 30	V
Drain current	DC (Note 1)	I_D	A
	Pulse (Note 1)	I_{DP}	
Drain power dissipation ($T_c = 25^\circ\text{C}$)	P_D	40	W
Single-pulse avalanche energy (Note 2)	E_{AS}	324	mJ
Avalanche current	I_{AR}	1	A
Repetitive avalanche energy (Note 3)	E_{AR}	4.0	mJ
Channel temperature	T_{ch}	150	$^\circ\text{C}$
Storage temperature range	T_{stg}	$-55 \sim 150$	$^\circ\text{C}$

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Thermal Characteristics

Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case	$R_{th(ch-c)}$	3.125	$^\circ\text{C/W}$
Thermal resistance, channel to ambient	$R_{th(ch-a)}$	125	$^\circ\text{C/W}$

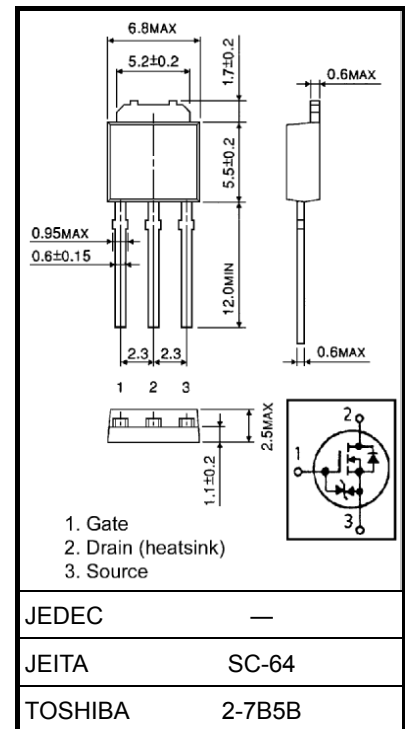
Note 1: Ensure that the channel temperature does not exceed 150°C .

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^\circ\text{C}$ (initial), $L = 594 \text{ mH}$, $R_G = 25 \Omega$, $I_{AR} = 1 \text{ A}$

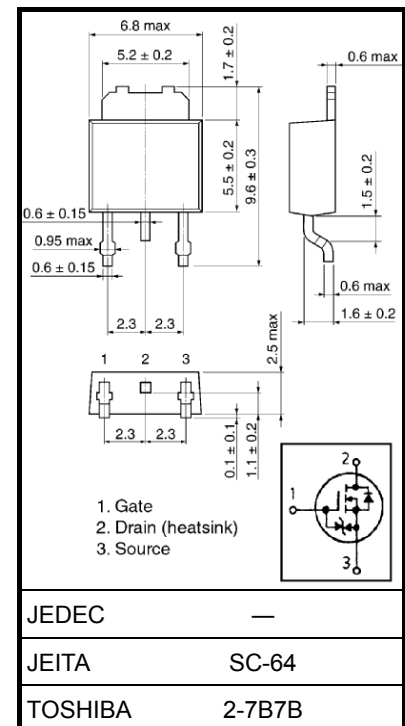
Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.

Unit: mm

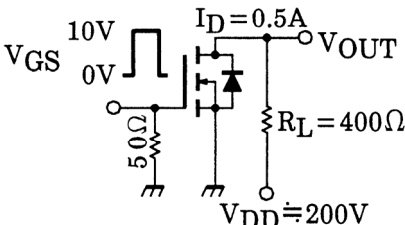


Weight: 0.36 g (typ.)



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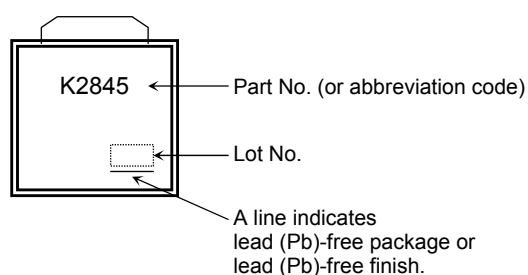
Electrical Characteristics (Ta = 25°C)

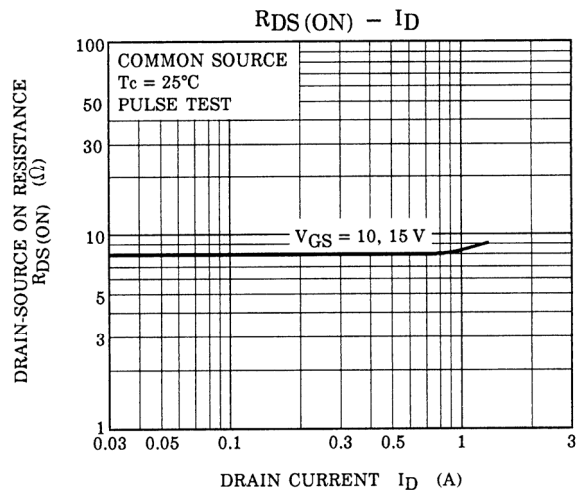
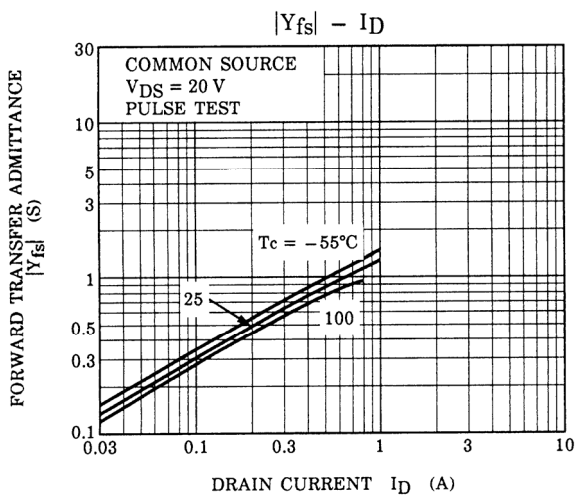
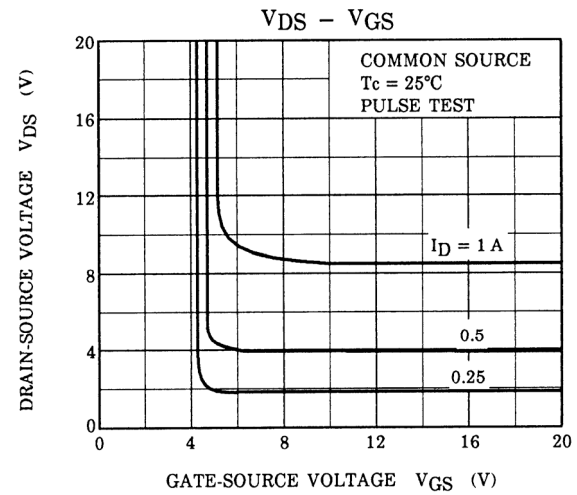
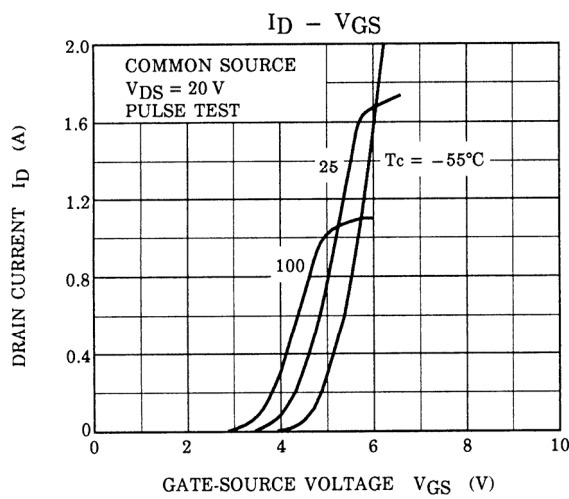
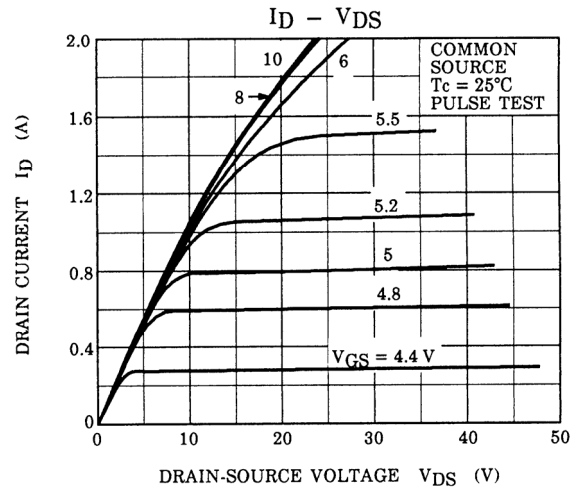
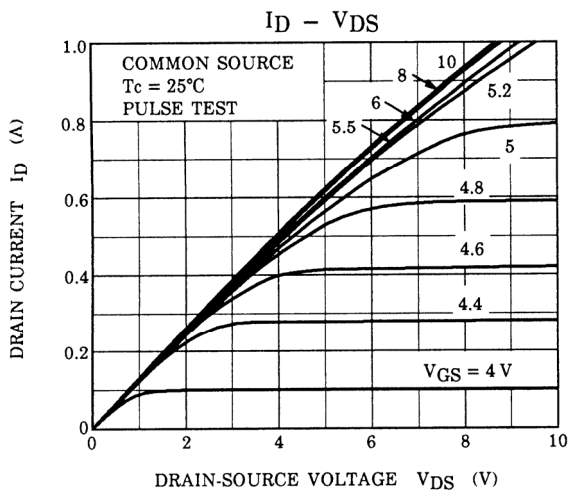
Characteristic		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	—	—	± 10	μA
Gate-source breakdown voltage		$V_{(BR) GSS}$	$I_G = \pm 10 \mu\text{A}, V_{DS} = 0 \text{ V}$	± 30	—	—	V
Drain cutoff current		I_{DSS}	$V_{DS} = 720 \text{ V}, V_{GS} = 0 \text{ V}$	—	—	100	μA
Drain-source breakdown voltage		$V_{(BR) DSS}$	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	900	—	—	V
Gate threshold voltage		V_{th}	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$	2.0	—	4.0	V
Drain-source ON-resistance		$R_{DS(ON)}$	$V_{GS} = 10 \text{ V}, I_D = 0.5 \text{ A}$	—	8.0	9.0	Ω
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = 20 \text{ V}, I_D = 0.5 \text{ A}$	0.45	0.9	—	S
Input capacitance		C_{iss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	—	350	—	pF
Reverse transfer capacitance		C_{rss}		—	8	—	
Output capacitance		C_{oss}		—	40	—	
Switching time	Rise time	t_r	 <p>$I_D = 0.5 \text{ A}$ $V_{GS} = 10 \text{ V}, 0 \text{ V}$ $R_L = 400 \Omega$ $V_{DD} \approx 200 \text{ V}$ Duty $\leq 1\%$, $t_w = 10 \mu\text{s}$</p>	—	20	—	ns
	Turn-on time	t_{on}		—	70	—	
	Fall time	t_f		—	30	—	
	Turn-off time	t_{off}		—	95	—	
Total gate charge (gate-source plus gate-drain)		Q_g	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 1 \text{ A}$	—	15	—	nC
Gate-source charge		Q_{gs}		—	6	—	
Gate-drain ("Miller") charge		Q_{gd}		—	9	—	

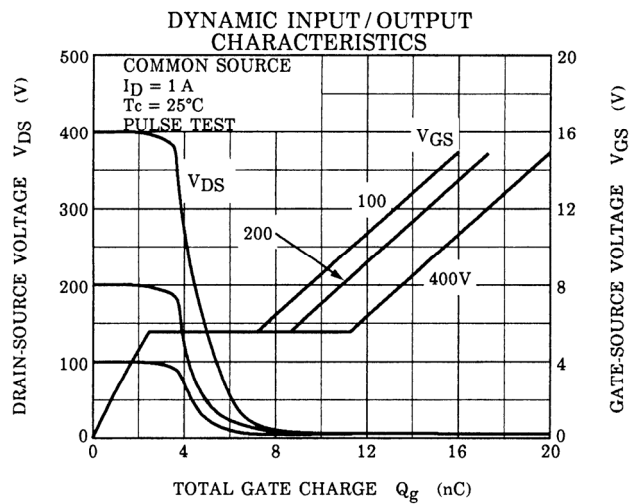
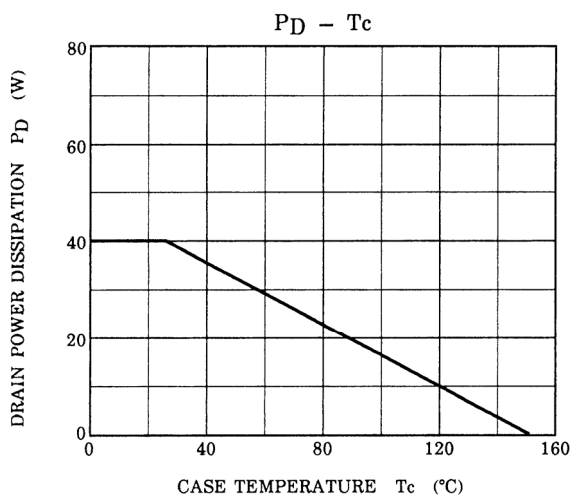
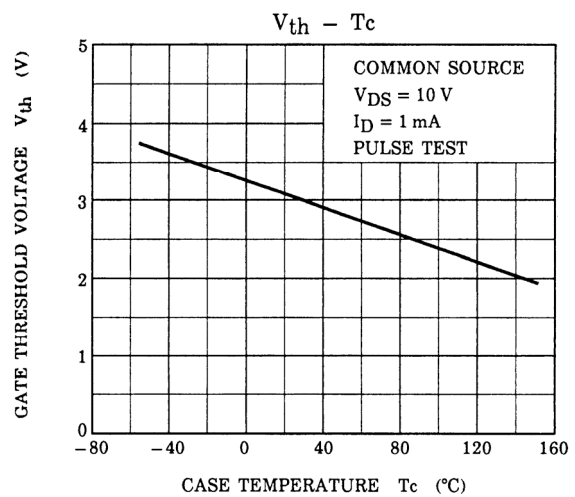
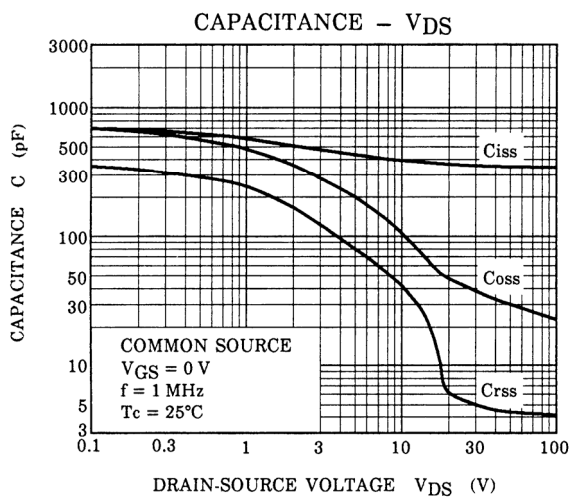
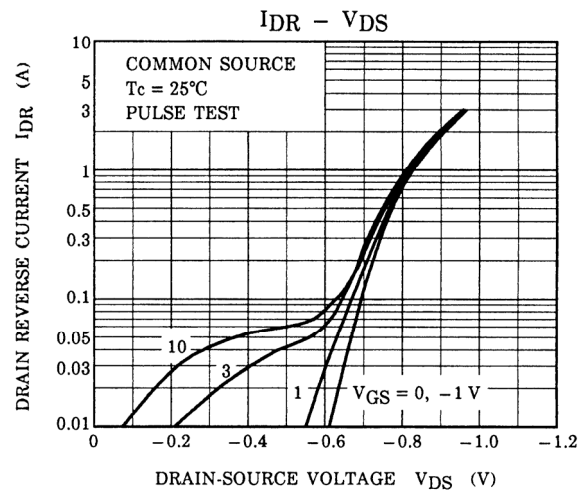
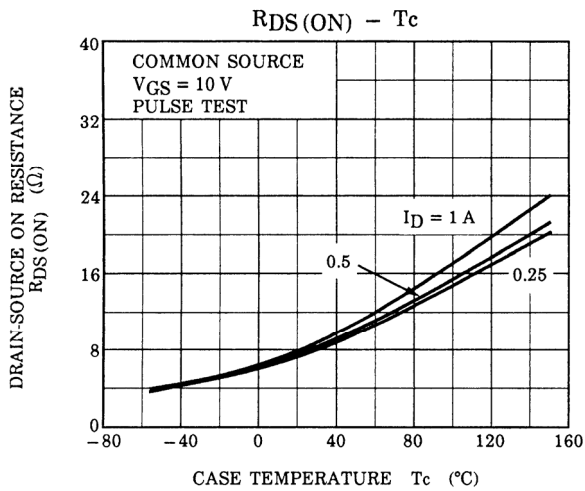
Source-Drain Ratings and Characteristics (Ta = 25°C)

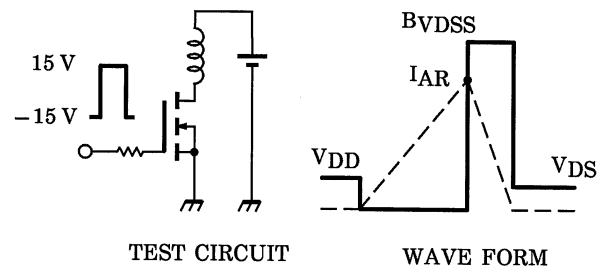
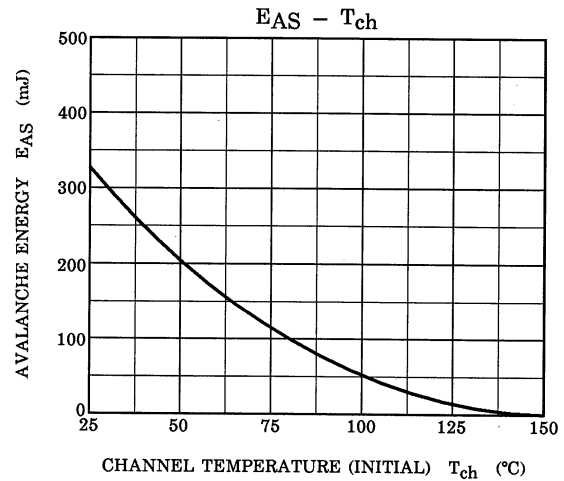
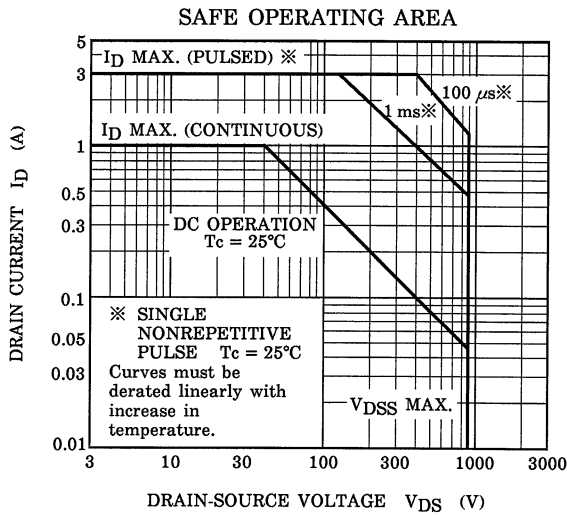
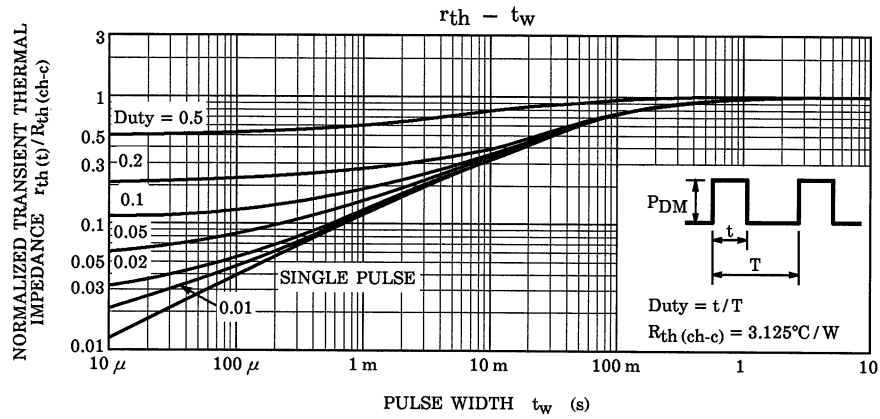
Characteristic	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR}	—	—	—	1	A
Pulse drain reverse current (Note 1)	I_{DRP}	—	—	—	3	A
Forward voltage (diode)	V_{DSF}	$I_{DR} = 1 \text{ A}, V_{GS} = 0 \text{ V}$	—	—	-1.9	V
Reverse recovery time	t_{rr}	$I_{DR} = 1 \text{ A}, V_{GS} = 0 \text{ V} \text{ d}I_{DR} / \text{d}t = 100 \text{ A} / \mu\text{s}$	—	750	—	ns
Reverse recovery charge	Q_{rr}		—	3	—	μC

Marking









$$R_G = 25 \, \Omega$$

$$V_{DD} = 90 \, \text{V}, L = 594 \, \text{mH}$$

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{V_{DS}}}{B_{V_{DS}} - V_{DD}} \right)$$

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